

PERFORMANCE SPECIFICATION SHEET

RELAYS, SOLID-STATE, SEALED, GENERAL SPECIFICATION FOR

This amendment forms a part of MIL-PRF-28750D dated 1 February 1999, and is approved for use by all Departments and Agencies of the Department of Defense.

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- \* Paragraph 2.2.1, STANDARDS, DEPARTMENT OF DEFENSE, add reference: "MIL-STD-461 – Requirements for the Control of Electromagnetic Interference Characteristics of Subsystems and Equipment."

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- \* Paragraph 3.12.27, delete: "(when specified, see 3.1)" and substitute "(when specified, see 3.1 and 6.11)"
- \* Add a paragraph "3.12.32 Electromagnetic interference (when specified, see 3.1). When solid state relays are tested as specified in 4.7.7.26 the conducted emission shall not exceed the specified value (see 3.1).

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- \* Paragraph 4.6.1.2.1, following the fourth sentence, add a new sentence: "Unless otherwise specified, the 5 percent shall only be applicable to +25°C tests."

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- \* Paragraph 4.7.7.21, delete: "(see 3.12.27)" and substitute "(see 3.12.27 and 6.11)"

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- \* Figure 4, delete: "DV/DT test setup" and substitute "DV/DT test setup (Set for maximum dv/dt with UUT disconnected.)"

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- \* Add a paragraph: "4.7.7.26 Electromagnetic interference, 25°C only (see 3.12.32)(For qualification and periodic inspections only). Solid state relays shall be subjected to electromagnetic interference as specified (see 3.1) in MIL-STD-461. Maximum broadband conducted emission on power lines, with a resistive load at maximum output voltage and current, during steady state and switching conditions, shall be within specifications (see 3.1)

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- \* Paragraph 4.7.17f., delete: "4.7.11" and substitute "4.7.7.22"

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- \* Add a paragraph: "6.11 Exponential rate of voltage rise (reference 3.12.27 and 4.7.7.21): The test described is generally intended for thyristor based output devices. Devices with FET and Bi-polar type outputs are not susceptible to false triggering and this test may not be applicable. If such FET/Bi-polar devices are used, for example, in armament firing or similar applications an alternative test of output capacitance and or let through current may be advisable."

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- \* Paragraphs A.3.4.7, A.3.4.7.1 and A.3.4.7.2, delete and substitute: "A.3.4.7 Delidding of SSR's. Hybrid construction SSR's may be delidded and relidded for rework or repair provided the delid-relid procedures, controls, qualification plan, and resulting data are baselined and approved by the qualifying activity. The number of delid-relid cycles allowed shall be in accordance with MIL-PRF-38534, Appendix E.

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Paragraph A.3.6.3 b., delete and substitute: "b. As a corrective action, if the lot fails the group A solderability test, insulation resistance (all terminals to case), seal, and visual/mechanical inspection shall be performed."

The margins of this amendment are marked with an asterisk to indicate where changes (additions, modifications, corrections, deletions) from the previous amendment were made. This was done as a convenience only and the Government assumes no liability whatsoever for any inaccuracies in these notations. Bidders and contractors are cautioned to evaluate the requirements of this document based on the entire content irrespective of the marginal notations and relationship to the last previous amendment.

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